

FORM PTO-1449 (Modified)	ATTY DOCKET NO. 02962-00042	SERIAL NO. Not yet assigned
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary.)	APPLICANT: Dryver R. Huston, Wolfgang Sauter and Peter A. Sonntag	
	FILING DATE: Filed herewith	GROUP: Not yet assigned

U.S. PTO
10/004746
12/04/01

REFERENCE DESIGNATION									U.S. PATENT DOCUMENTS					
EXAMINERS INITIALS		DOCUMENT NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)	
SAT	AA	6	0	5	0	1	3	8	Apr. 18, 2000	Lynch et al.	73	150		
SAT	AB	5	5	4	6	1	8	4	Aug. 13, 1996	Downs	356	345		
SAT	AC	5	5	2	6	1	1	4	June 11, 1996	Eselun	356	345		
SAT	AD	4	7	2	9	6	5	4	Mar. 8, 1988	Akuta et al.	356	4.5		
	AE													
	AF													
	AG													

FOREIGN PATENT DOCUMENTS														
		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
		YES	NO											
	AH													
	AI													
	AJ													
	AK													

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)									
SAT	AL	Bulge and Blister Testing of Thin Films and Their Interfaces, Ph.D. Dissertation, Stanford University, by Robert J. Hohlfelder (1999); (specifically, pgs. 95-120, Chapter 6, <i>It's a nice theory, but how do you run experiments?</i>) http://mse.stanford.edu/people/faculty/nix/people/past_members/rjhThesis/thesis.html							
SAT	AM	Application of Bulge Testing Techniques in Determining the Mechanical Properties of Thin Films, Thesis by Jason Gill, University of Vermont (May, 1998)							
SAT	AN	Automation of Temperature Measurement by Laser, by FEI Yue, XI Yangang, CHEN Yuanjie, MA Xiufang, SHEN Yuanhua, Department of Physics, Fudan University, Shanaghai, China, Proceedings of SPIE, Vol. 3558, pgs. 87-92, Automated Optical Inspection for Industry: Theory, Technology, and Applications II (August, 1998)							

EXAMINER SAT Turner	DATE CONSIDERED 9-10-03
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.